

DECLARATION OF CONFORMITY

According to EN/ISO/IEC 17050-1

QUALITY MANAGEMENT SYSTEM

CERTIFIED BY DNV

= ISO 9001:2008 ====

This declaration of conformity is issued under the sole responsibility of the manufacturer.

Manufacturer's Name: N-TRON Corporation

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Hereby, N-TRON Corporation declares that these industrial Ethernet devices are in compliance with the essential requirements and other relevant provisions of Directives 1999/5/EC and 2004/108/EC.

Listing of conforming devices:

108M12 IP67 Rated 8 port 10/100BaseTX Industrial Ethernet Switch with

> M12 D-Coded Female 4-Pin Connectors, Bulkhead Mountable Input Voltage 10-30 VDC; Operating Temperature -40°C to 70°C

Standards of conformance: This product herewith complies with the requirements of standards presented below.

Commission **Industry Canada**



- US Federal Communications ANSI C63.4-2001: Method of Measurements of Radio-Noise Emissions from Low-Voltage Electrical and Electronic Equipment in the 9kHz to 40GHz
 - US Code of Federal Regulations (CFR): Title 47, Part 15, Radio Frequency Devices, Subpart B, Unintentional Radiators (October 2005)
 - Industry Canada ICES-003 Issue 3: Digital Apparatus (November 1997)

European Union Conformité Européenne



- 2004/108/EC Electromagnetic Compatibility
- EN 55011:1998+A1+A2 Industrial, Scientific and Medical (ISM) Radio-Frequency Equipment – Radio Disturbance Characteristics
- IEC 61000-4-2 Ed. 1.2 Electrostatic Discharge Immunity Test
- IEC 61000-4-3 Ed. 2.1 Radiated, Radio-Frequency, Electromagnetic Field **Immunity Test**
- IEC 61000-4-4 2nd Ed. Electrical Fast Transient/Burst Immunity Test
- IEC 61000-4-5 2nd Ed. Surge Immunity Test
- IEC 61000-4-6 Ed. 2.1 Immunity to Conducted Disturbances Induced by Radio-Frequency Fields
- IEC 61000-4-11 2nd Ed. Voltage Dips, Short Interruptions and Voltage Variations Immunity Tests

Mr. Jerry Simmons Regulatory Manager NVLAP Lab. Accredited to ISO/IEC 17025:2005

Electromagnetic Compatibility and Telecommunications

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Test Report: 10-0341-ARPT

DoC ID: N-TRON DoC 108M12

Date of Current DoC: December 9, 2010-C